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**SILICON NPN PHOTO TRANSISTOR**

**AT404-PT-02**

**DATA SHEET**

REV. : 1.0

DATE : 20-Apr.-2005

**FEATURE:**

- Fast Response Time.
- High Photo Sensitivity.
- Visible Light Cut-Off Type.
- Lead Free product, in compliance with RoHS.

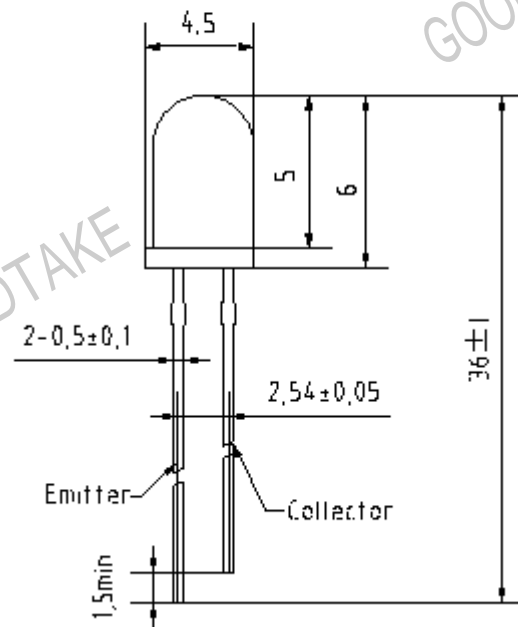
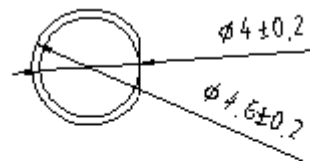
**DESCRIPTIONS:**

- AT404-PT-02 is a high speed and high sensitive silicon NPN phototransistor with exceptionally stable characteristics and high illumination sensitivity.
- Mounted in 5mm diameter black epoxy package.

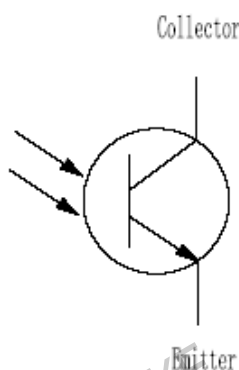
**APPLICATIONS:**

- Infrared Applied System.
- Floppy Disk Drive.
- Opto-Electronic Switch.

**DIMENSIONS:**



**INTERNAL CIRCUIT:**



**NOTE:** 1. All dimensions are in millimeter, tolerance is  $\pm 0.5$  unless otherwise noted.  
 2. Epoxy meniscus extends  $\leq 1$  mm down to the lead is allowed.

### ■ ABSOLUTE MAXIMUM RATINGS AT Ta=25°C

| Parameter                           | Symbol           | Ratings                             | Unit |
|-------------------------------------|------------------|-------------------------------------|------|
| Power Dissipation                   | P <sub>D</sub>   | 100                                 | mW   |
| Collector-Emitter Breakdown Voltage | V <sub>CEO</sub> | 30                                  | V    |
| Emitter-Collector Breakdown Voltage | V <sub>ECO</sub> | 5                                   | V    |
| Operating Temperature               | T <sub>opr</sub> | -40~+85                             | °C   |
| Storage Temperature                 | T <sub>stg</sub> | -55~+100                            | °C   |
| Soldering Temperature               | T <sub>sol</sub> | 270°C for 6 sec Max (2mm from Body) |      |

### ■ TYPICAL ELECTRICAL & OPTICAL CHARACTERISTICS (Ta=25°C)

| Parameter                            | Symbol               | Min. | Type | Max. | Unit | Test Condition  |
|--------------------------------------|----------------------|------|------|------|------|---|
| Collector-Emitter Breakdown Voltage  | V <sub>(BR)CEO</sub> | 30   |      |      | V    | I <sub>C</sub> =100μA<br>E <sub>e</sub> =0mW/cm <sup>2</sup>        |
| Emitter-Collector Breakdown Voltage  | V <sub>(BR)ECO</sub> | 5    |      |      | V    | I <sub>E</sub> =100μA<br>E <sub>e</sub> =0mW/cm <sup>2</sup>        |
| Collector-Emitter Saturation Voltage | V <sub>CE(sat)</sub> |      |      | 0.2  | V    | I <sub>C</sub> =2mA I <sub>B</sub> =100μA                           |
| Rise Time                            | T <sub>r</sub>       |      | 5    |      | μS   | V <sub>CE</sub> =5V<br>I <sub>C</sub> =1mA<br>R <sub>L</sub> =1000Ω |
| Fall Time                            | T <sub>f</sub>       |      | 5    |      | μS   |   |
| Collector Dark Current               | I <sub>CEO</sub>     |      |      | 100  | nA   | V <sub>CE</sub> =10V<br>E <sub>e</sub> =0mW/cm <sup>2</sup>         |
| On State Collector Current           | I <sub>C(on)</sub>   | 8    |      |      | mA   | 5V<br>E <sub>e</sub> =1mW/cm <sup>2</sup><br>λ <sub>p</sub> =940nm  |
| Peak Wavelength of Sensitive         | λ <sub>p</sub>       |      | 940  |      | nm   |   |

**■ RELIABILITY TEST ITEMS AND CONDITIONS:**

| <b>NO</b> | <b>Item</b>                                   | <b>Test Conditions</b>  | <b>Test Hours/Cycle</b> | <b>Sample Quantity</b> | <b>Test Result</b> |
|-----------|---|---|-------------------------|------------------------|--------------------|
| <b>1</b>  | <b>Solder Heat</b>                            | <b>TEMP: 270°C ± 3°C</b>  | <b>10 SEC</b>           | <b>11 pcs</b>          | <b>0 DEFECT</b>    |
| <b>2</b>  | <b>Temperature Cycle</b>                      | <b>H: +85°C 180min</b><br>$\updownarrow$ <b>10min</b><br><b>L: -25°C 180min</b> | <b>16 cycles</b>        | <b>22 pcs</b>          | <b>0 DEFECT</b>    |
| <b>3</b>  | <b>Thermal Shock</b>                          | <b>H: +85°C 30min</b><br>$\updownarrow$ <b>30sec</b><br><b>L: -25°C 30min</b>   | <b>10 cycles</b>        | <b>11 pcs</b>          | <b>0 DEFECT</b>    |
| <b>4</b>  | <b>High Temperature Storage</b>               | <b>TEMP: +25°C</b>  | <b>1000 HRS</b>         | <b>22 pcs</b>          | <b>0 DEFECT</b>    |
| <b>5</b>  | <b>Low Temperature Storage</b>                | <b>TEMP: -25°C</b>  | <b>1000 HRS</b>         | <b>22 pcs</b>          | <b>0 DEFECT</b>    |
| <b>6</b>  | <b>High Temperature High Humidity Storage</b> | <b>85°C / 93% RH</b>  | <b>1000HRS</b>          | <b>22 pcs</b>          | <b>0 DEFECT</b>    |

■ TYPICAL ELECTRO-OPTICAL CHARACTERISTICS CURVES:

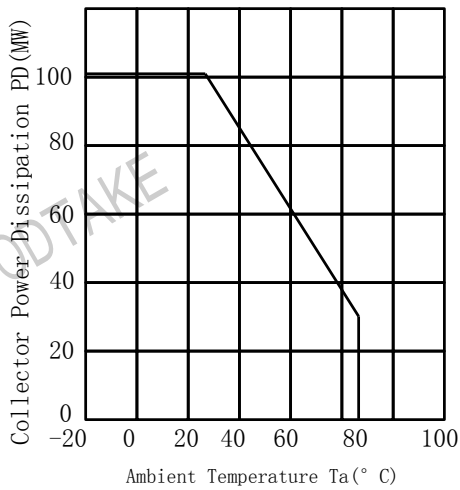


FIG. 1 Collector Pd vs Ta

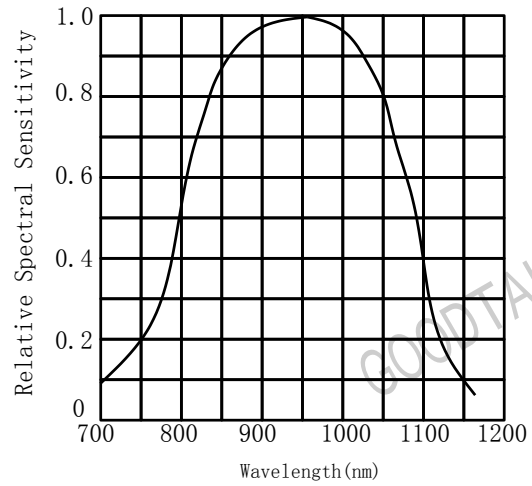


FIG. 2 Spectral Sensitivity

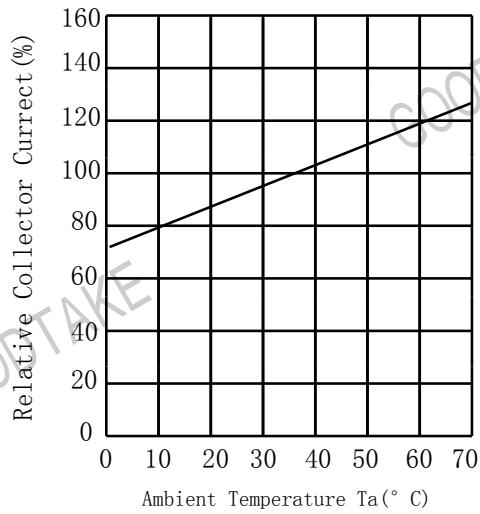


FIG. 3 Relative Ic vs. Ta

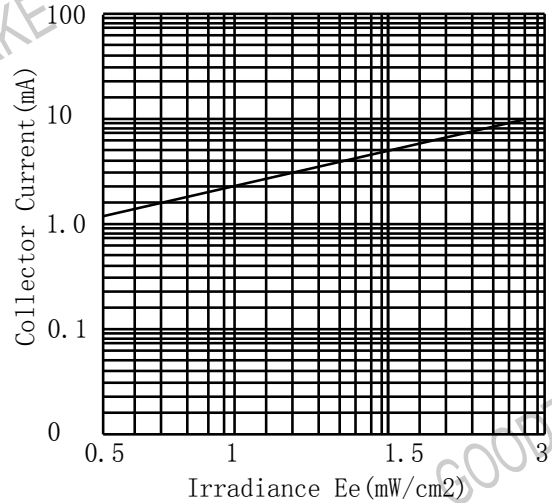


FIG. 4 Ic vs Iv

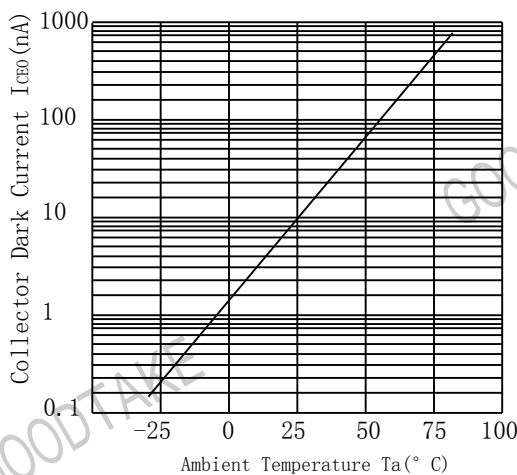


FIG. 5 Id vs Ta